

3rd International Workshop on DEPFET Detectors and Applications

Wednesday, 7 October 2009

DEPFET - Lecture Room (11:00 - 12:30)

time	[id] title	presenter
11:00	[32] PXD6 - Design and Technology Status	RICHTER, Rainer
11:20	[33] Radiation Test Plans	RITTER, Andreas
11:35	[34] Alternative Readout Schemes from ILC to Belle II	RUMMEL, Stefan
11:50	[35] DCD Measurements with Matrix	KOCH, Manuel
12:05	[36] DCD - Single vs Double Sampling	PERIC, Ivan
12:20	[37] Discussion: Do we have to change the Readout Scheme?	